

(March 4, 2002)

Sheet 1 of 1

Form PTO-1449 U.S. Dept. of Commerce (Rev. 8-83) PATENT & TRADEMARK OFFICE  <b>INFORMATION DISCLOSURE STATEMENT</b> (Use several sheets if necessary)	ATTY. DOCKET NO. 66376-279-7	SERIAL NO.
	APPLICANT Herbert Thanner et al.	
	FILING DATE March 4, 2002	GROUP

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## U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE

## FOREIGN PATENT DOCUMENTS

	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB CLASS	TRANSLATION YES NO

## OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)

<i>1/ma</i>	A.W. Warner, "Design and Performance of Ultraprecise 2.5-mc Quartz Crystal Units," Bell Sys. Techn. J., Sept. 1960, pp. 1193-1217.
<i>kan</i>	Ch. Longet et al., "An Electrodeless BT Cut, 5 <sup>th</sup> Overtone Quartz Crystal Resonator at 50 MHZ," EFTF, 1995, pp. 141-145.
<i>kan</i>	R. C. Smythe et al., "Langasite, Langanite, and Langatate Resonators: Recent Results," Joint Meeting EFTF-IEEE IFCS, 1999, pp. 816-820.
<i>kan</i>	<u>IEEE Standard on Piezoelectricity</u> , The Institute of Electrical and Electronics Engineers, New York, N.Y. (Jan. 29, 1988).
<i>kan</i>	<u>International Tables for X-Ray Crystallography</u> , The Kynoch Press, Birmingham, England (1969), pg. 255.
<i>kan</i>	B. V. Mill et al., "Synthesis, Growth and Some Properties of Single Crystals with the Ca <sub>3</sub> Ga <sub>2</sub> Ge <sub>4</sub> O <sub>14</sub> Structure," Joint Meeting EFTF-IEEE IFCS, 1999, pp. 829-834.

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Initial if citation considered, whether or not citation is in conformance with M.P.E.P. 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.



(January 29, 2003)

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ATTY. DOCKET NO.  
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**10/086,537**

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**Herbert THANNER et al.**

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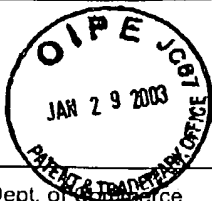
<i>KRM</i>	<b>C. Reiter et al., "Elastic Constants and Temperature-Compensated Orientations of GaPO<sub>4</sub>," 15<sup>th</sup> European Frequency and Time Forum Neuchatel, XP008009573, 6 March 2001, pp. 50-54.</b>
<i>KRM</i>	<b>E. Philippot et al., "A Quartz-like Material...Characterization" in J. Crystal Growth, 130, No. 1/2, May 1993, pp. 195-208.</b>
<i>KRM</i>	<b>A. Zarka et al., "Studies of GaPO<sub>4</sub> Crystals and Resonators," 1996 IEEE International Frequency Control Symposium, 1996, pp. 66-71.</b>

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<i>kmw</i>	<b>S.A. Ssakharov et al., "Application of Langasite...Modes," 1992 IEEE Frequency Control Symposium, 1992, pp. 713-723.</b>
<i>kmw</i>	<b>H. Fritze et al., "High Temperature...Langasite" in Sensors and Actuators B 76, 1 June 2001, pp. 103-107.</b>
<i>kmw</i>	<b>M. F. Dubovik et al., "Influence...Crystals," 1996 IEEE International Frequency Control Symposium, 1996, pp. 84-89.</b>

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